

# **Product Specification**

# NVMFS5834NL

N-Channel Enhancement Mode MOSFET











#### **Descriptions**

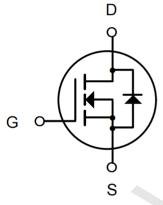
The NVMFS5834NL uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **Features**

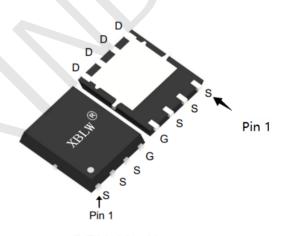
- $V_{DS} = 40V_{ID} = 55A$
- $ightharpoonup R_{DS(ON)} < 8.5 m\Omega V_{GS} = 10 V$

### **Applications**

- Battery protection
- Load switch
- Uninterruptible power supply







DFN5X6-8L

### **Ordering Information**

<b>Product Model</b>	Package Type	Marking	Packing	Packing Qty
NVMFS5834NL	DFN5X6-8L	NVMFS5834	Tape	5000Pcs/Reel



# **Absolute Maximum Ratings** (T<sub>c</sub>=25 ℃ unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	40	V
$V_{GS}$	Gate-Source Voltage	±20	V
<b>I</b> ⊳@ <b>T</b> c= <b>25</b> °C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	55	Α
<b>Љ@T</b> c= <b>100</b> ℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	41	Α
$\mathbf{I}_{DM}$	Pulsed Drain Current <sup>2</sup>	280	Α
EAS	Single Pulse Avalanche Energy <sup>3</sup>	76	mJ
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
Tı	Operating Junction Temperature Range	-55 to 150	°C

# NVMFS5834NL

#### N-Channel Enhancement Mode MOSFET

#### **Electrical Characteristics** (T<sub>c</sub>=25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ =0 $V$ , $I_D$ =250 $u$ A	40			V	
Б	Static Desire Source On Desistance?	V <sub>GS</sub> =10V , I <sub>D</sub> =15A	V <sub>GS</sub> =10V , I <sub>D</sub> =15A 6.5		8.5	mO	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =4.5V , I <sub>D</sub> =8A		9	12	mΩ	
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS}$ = $V_{DS}$ , $I_D$ =250uA	1.2	1.8	2.5	V	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =40V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA	
IDSS		$V_{DS}$ =40V , $V_{GS}$ =0V , $T_J$ =55°C			5		
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{\text{GS}}=\pm20\text{V}$ , $V_{\text{DS}}$ =0V		-	±100	nA	
$R_g$	Gate Resistance	$V_{DS}$ =0 $V$ , $V_{GS}$ =0 $V$ , f=1 $MHz$		2.0		Ω	
$Q_g$	Total Gate Charge (4.5V)			19.7			
$Q_{gs}$	Gate-Source Charge	$V_{DS}$ =20V , $V_{GS}$ =10V , $I_D$ =10A		2.8		nC	
$Q_{gd}$	Gate-Drain Charge			5.1			
T <sub>d(on)</sub>	Turn-On Delay Time			13.2			
Tr	Rise Time	$V_{DD}$ =15V , $V_{GS}$ =10V , $R_{G}$ =3.3 $\Omega$		2.2		ns	
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =1A		72			
T <sub>f</sub>	Fall Time			4.5			
C <sub>iss</sub>	Input Capacitance			6000			
Coss	Output Capacitance	$V_{DS}$ =15V , $V_{GS}$ =0V , f=1MHz		1509		рF	
C <sub>rss</sub>	Reverse Transfer Capacitance			129			
ls	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			140	Α	
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1	V	

#### Note:

- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2% .
- 3. The EAS data shows Max. rating . The test condition is  $V_{DD} = 25 V_{\nu} V_{GS} = 10 V_{\nu} L = 0.1 mH$ ,  $I_{AS} = 31 A$ .
- 4.The power dissipation is limited by  $150\,^{\circ}\mathrm{C}$  junction temperature .
- 5.The data is theoretically the same as  $I_{\text{D}}$  and  $I_{\text{DM}}$ , in real applications , should be limited by total power dissipation.



# **Typical Characteristics**

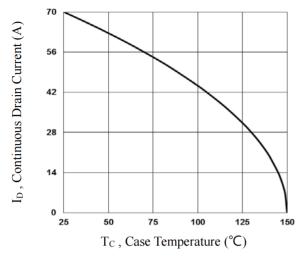
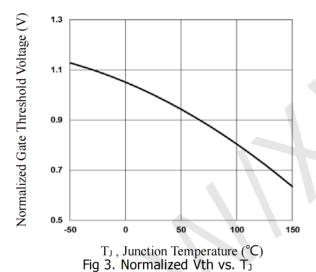


Fig 1. Continuous Drain Current vs. T<sub>C</sub>



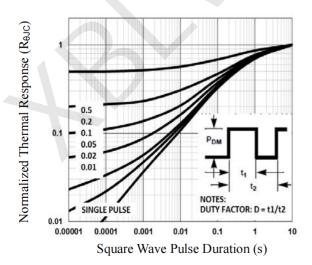


Fig 5. Normalized Transient Impedance

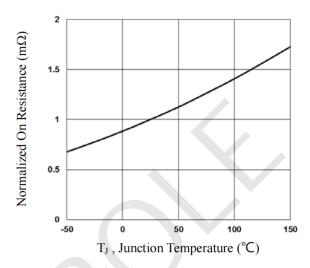
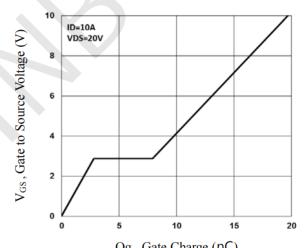


Fig 2. Normalized RDSON vs. T<sub>J</sub>



 $\label{eq:Qg_def} Qg \ , \ Gate \ Charge \ (nC)$  Fig 4. Gate Charge Waveform

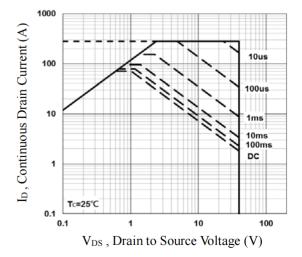


Fig 6. Maximum Safe Operation Area



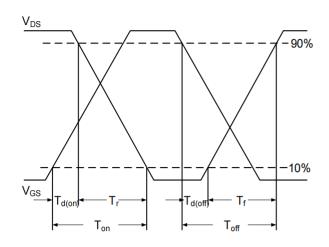


Fig 7. Switching Time Waveform

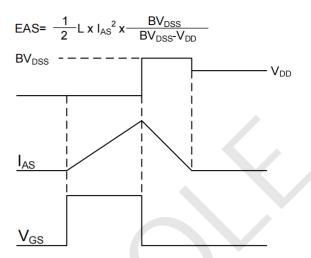


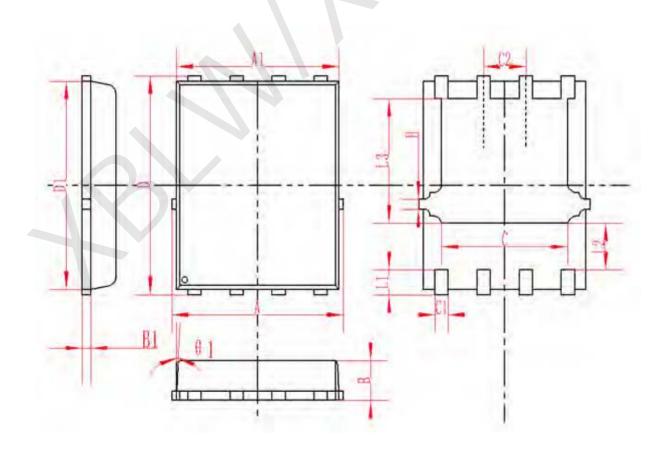
Fig 8. EAS Waveform



# **Package Information**

#### DFN5X6-8L

SYMBOL	MM			INCH			
	MIN	NOM	MAX	MIN	NOM	MAX	
Α	4.95	5	5.05	0.195	0.197	0.199	
A1	4.82	4.9	4.98	0.190	0.193	0.196	
D	5.98	6	6.02	0.235	0.236	0.237	
D1	5.67	5.75	5.83	0.223	0.226	0.230	
В	0.9	0.95	1	0.035	0.037	0.039	
B1	0.254REF		0.010REF				
С	3.95	4	4.05	0.156	0.157	0.159	
C1	0.35	0.4	0.45	0.014	0.016	0.018	
C2	1.27TYP		0.5TYP				
θ1	8°	10°	12°	8°	10°	12°	
L1	0.63	0.64	0.65	0.025	0.025	0.026	
L2	1.2	1.3	1.4	0.047	0.051	0.055	
L3	3.415	3.42	3.425	0.134	0.135	0.135	
Н	0.24	0.25	0.26	0.009	0.010	0.010	



## NVMFS5834NL N-Channel Enhancement Mode MOSFET

#### Statement:

- XBLW reserves the right to modify the product manual without prior notice! Before placing an order, customers need to confirm whether the obtained information is the latest version and verify the completeness of the relevant information.
- Any semiconductor product may malfunction under specified conditions. When using XBLW products for system design and overall manufacturing, the buyer is responsible for complying with safety standards and taking appropriate safety measures to avoid risks that may cause personal injury or property damage.
- XBLW products have not been licensed for life support, military, and aerospace applications, and therefore XBLW is not responsible for any consequences arising from the use of this product in these areas.
- If any or all XBLW products (including technical data, services) described or contained in this document are subject to any applicable local export control laws and regulations, they may not be exported without an export license from the relevant authorities in accordance with such laws.
- The specifications of any and all XBLW products described or contained in this document specify the performance, characteristics, and functionality of said products in their standalone state, but do not guarantee the performance, characteristics, and functionality of said products installed in Customer's products or equipment. In order to verify symptoms and conditions that cannot be evaluated in a standalone device, the Customer should ultimately evaluate and test the device installed in the Customer's product device.
- XBLW documentation is only allowed to be copied without any alteration of the content and with the relevant authorization. XBLW assumes no responsibility or liability for altered documents.
- XBLW is committed to becoming the preferred semiconductor brand for customers, and XBLW will strive to provide customers with better performance and better quality products.